DS05-11023-2E

MEMORY CMOS

2 × 2 M × 4 BITS SYNCHRONOUS DYNAMIC RAM

MB81117422A-125/-100/-84/-67

CMOS 2 BANKS OF 2,097,152-WORD × 4 BITS SYNCHRONOUS DYNAMIC RANDOM ACCESS MEMORY

■ DESCRIPTION

The Fujitsu MB81117422A is a CMOS Synchronous Dynamic Random Access Memory (SDRAM) containing 16,777,216 memory cells accessible in an 4-bit format. The MB81117422A features a fully synchronous operation referenced to a positive edge clock whereby all operations are synchronized at a clock input which enables high performance and simple user interface coexistence. The MB81117422A SDRAM is designed to reduce the complexity of using a standard dynamic RAM (DRAM) which requires many control signal timing constraints, and may improve data bandwidth of memory as much as 5 times more than a standard DRAM.

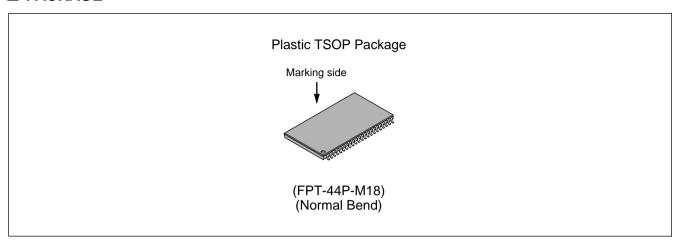
The MB81117422A is ideally suited for laser printers, high resolution graphic adapters, accelerators and other applications where an extremely large memory and bandwidth are required and where a simple interface is needed.

■ PRODUCT LINE & FEATURES

Parameter	MB81117422A								
Farameter	-125	-100	-84	-67					
Clock Frequency	125 MHz max.	100 MHz max.	84 MHz max.	67 MHz max.					
Burst Mode Cycle Time	8 ns min.	10 ns min.	12 ns min.	15 ns min.					
RAS Access Time	45 ns max.	54 ns max.	56 ns max.	60 ns max.					
CAS Access Time	21 ns max.	24 ns max.	26 ns max.	30 ns max.					
Access Time From Clock (CL = 3)	7.5 ns max.	8.5 ns max.	8.5 ns max.	9 ns max.					
Operating Current (Two banks active)	140 mA max. 130 mA max. 120 mA max. 110 mA ma								
Power Down Mode Current		2 mA	max.						

- Single +3.3 V Supply ±0.3 V tolerance
- LVTTL compatible I/O
- 2 K refresh cycles every 32.8 ms
- Dual bank operation
- Byte control by DQM
- Burst Read/Write operation and burst read/ single write operation capability
- Programmable burst type, burst length, and CAS latency
- Auto and Self Refresh (every 16 μs)
- CKE power down mode
- Output Enable and Input Data Mask

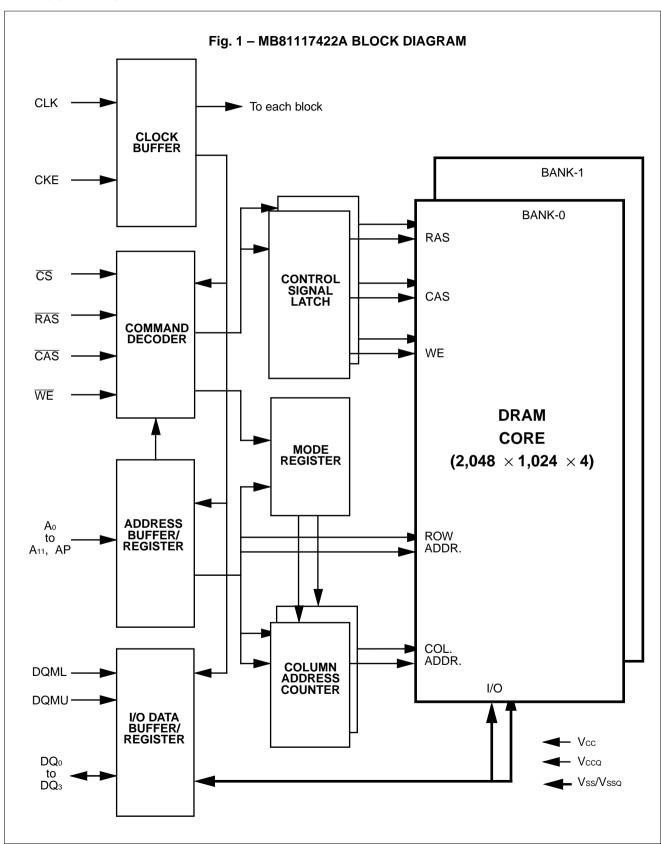
■ PACKAGE



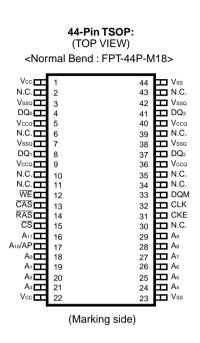
Package and Ordering Information

- 44-pin plastic (400 mil) TSOP-II, order as MB81117422A-xxxFN (2K Refresh)

■ BLOCK DIAGRAM



■ PIN ASSIGNMENTS AND DESCRIPTIONS



Pin Number	Symbol	Description
1, 5, 9, 22, 36, 40	Vcc, Vccq	Supply Voltage
4, 8, 37, 41	DQ ₀ to DQ ₃	Data I/O
3, 7, 23, 38, 42, 44	Vss, Vssq*	Ground
2, 6, 10, 11, 30, 34, 35, 39, 43	N.C.	No Connection
12	WE	Write Enable
13	CAS	Column Address Strobe
14	RAS	Row Address Strobe
15	<u>CS</u>	Chip Select
16	A ₁₁ (BA)	Bank Select
17	AP	Auto Precharge Enable
17, 18, 19, 20, 21, 24, 25, 26, 27, 28, 29	A ₀ to A ₁₀	Address Input Row : A ₀ to A ₁₀ Column : A ₀ to A ₉
31	CKE	Clock Enable
32	CLK	Clock Input
33	DQM	Input Mask/Output Enable

^{*:} These pins are connected internally in the chip.

■ FUNCTION TRUTH TABLE

COMMAND TRUTH TABLE

Function	Notes	Symbol	CI	KE	CS	RAS	CAS	WE	A 11	A 10	A ₉ to A ₀	
Tunction	NOICS	Symbol	n-1	n	CS	INAG	CAS	VV L	(BA)	(AP)	71310710	
Device Deselect	*5	DESL	Н	Х	Н	Х	Х	Х	Х	Х	Х	
No Operation	*5	NOP	Н	Х	L	Н	Н	Н	Х	Х	Х	
Burst Stop	*6	BST	Н	Х	L	Н	Н	L	Х	Х	Х	
Read	*7	READ	Н	Х	L	Н	L	Н	V	L	V	
Read with Auto-precharge	*7	READA	Н	Х	L	Н	L	Н	V	Н	V	
Write	*7	WRIT	Н	Х	L	Н	L	L	V	L	V	
Write with Auto-precharge	*7	WRITA	Н	Х	L	Н	L	L	V	Н	V	
Bank Active (RAS)	*8	ACTV	Н	Х	L	L	Н	Н	V	V	V	
Precharge Single Bank		PRE	Н	Х	L	L	Н	L	V	L	Х	
Precharge All Banks		PALL	Н	Χ	L	L	Н	L	Χ	Н	Х	
Mode Register Set	*9,10	MRS	Н	Х	L	L	L	L	V	L	V	

Notes: *1. V = Valid, L = Logic Low, H = Logic High, X = either L or H.

- *2. All commands assumes no CSUS command on previous rising edge of clock.
- *3. All commands are assumed to be valid state transitions.
- *4. All inputs are latched on the rising edge of clock.
- *5. NOP and DESL commands have the same effect on the part.
- *6. BST command is effective only during full colmun burst read or write.
- *7. READ, READA, WRIT and WRITA commands should only be issued after the corresponding bank has been activated (ACTV command). Refer to STATE DIAGRAM.
- *8. ACTV command should only be issued after corresponding bank has been precharged (PRE or PALL command).
- *9. Required after power up.
- *10. MRS command should only be issued after all banks have been precharged (PRE or PALL command). Refer to STATE DIAGRAM.

DQM TRUTH TABLE

Function	Command	CI	DQM	
Function	Command	n-1	n	DQIVI
Data Write/Output Enable	ENBL	Н	X	L
Data Mask/Output Disable	MASK	Н	X	Н

CKE TRUTH TABLE

Current	Function	Notes	Current of	CI	ΚE	CS	RAS	CAS	WE	A 11	A 10	A ₉ to A ₀
State	Function	Notes	Symbol	n-1	n	CS	KAS	CAS	VVE	(BA)	(AP)	A9 tO A0
Bank Active	Clock Suspend Mode Entry	*1	CSUS	Н	L	Х	Х	Х	Х	Х	Х	Х
Any	Clock Suspend Continue	*1		L	L	Х	Х	Х	Х	Χ	Х	Х
Clock Suspend	Clock Suspend Mode Exit			L	Н	Х	Х	Х	Х	Х	Х	Х
Idle	Auto-refresh Command	*2	REF	Н	Н	L	L	L	Н	Х	Х	Х
Idle	Self-refresh Entry	*2	SELF	Н	L	L	L	L	Н	Χ	Х	Х
Self Refresh	Self-refresh Exit		SELFX	L	Н	L	Н	Н	Н	Х	Х	Х
Sell Reliesh	Seli-refresh Exit		SELFA	L	Н	Н	Х	Х	Χ	Х	Х	Х
Idlo	Dower Down Entry		PD	Н	L	L	Н	Н	Н	Χ	Х	Х
Idle	Power Down Entry		PD	Н	L	Н	Х	Х	Χ	Х	Х	Х
Dracharga	Davier Davie Entry		DD	Н	L	L	Н	Н	Н	Х	Х	Х
Precharge	Power Down Entry		PD	Н	L	Н	Х	Х	Χ	Χ	Х	Х
Dools Astins	Davier Davie Entry	*2	DD	Н	L	L	L	Н	L	V	L	Х
Back Active	Power Down Entry	*3	PD	Н	L	L	L	Н	L	Х	Н	Х
Dawar Dawa	Davier Davie Evit			L	Н	L	Н	Н	Н	Х	Х	Х
Power Down	Power Down Exit			L	Н	Н	Х	Х	Х	Х	Х	Х

Notes: *1. The CSUS command requires that at least one bank is active. Refer to STATE DIAGRAM.

- *2. REF and SELF commands should only be issued after all banks have been precharged (PRE or PALL command). Refer to STATE DIAGRAM.
- *3. PD command should be issud after all banks have been precharged (PRE or PALL command). If a bank or all banks are in active state, PD command can be issued in conjuction with PRE or PALL command whichever Precharge command makes all banks in idle state.

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OPERATION COMMAND TABLE (Aplicable to single bank)

Current State	CS	RAS	CAS	WE	Addr	Command	Function Notes
Idle	Н	Х	Х	Х	Х	DESL	NOP
	L	Н	Н	Н	Х	NOP	NOP
	L	Н	Н	L	Х	BST	NOP
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal
	L	L	Н	Н	BA, RA	ACTV	Bank Active after tRCD
	L	L	Н	L	BA, AP	PRE/PALL	NOP
	L	L	L	Н	Х	REF/SELF	Auto Refresh or Self Refresh *3
	L	L	L	L	MODE	MRS	Mode Register Set (Idle after trsc) *3
Bank Active	Н	Х	Х	Х	Х	DESL	NOP
	L	Н	Н	Н	Х	NOP	NOP
	L	Н	L	Н	BA, CA, AP	READ/READA	Begin Read; Determine AP
	L	Н	Н	L	Х	BST	NOP
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Begin Write; Determine AP
	L	L	Н	Н	BA, RA	ACTV	Illegal *2
	L	L	Н	L	BA, AP	PRE/PALL	Precharge; Determine Precharge Type
	L	L	L	Н	Х	REF/SELF	Illegal
	L	L	L	L	MODE	MRS	Illegal

Current State	CS	RAS	CAS	WE	Addr	Command	Function	Notes
Read	Н	х	х	х	Х	DESL	NOP (Continue Burst to End → Bank Active)	
	L	Н	Н	Н	Х	NOP	NOP (Continue Burst to End → Bank Active)	
	L	Н	Н	L	Х	BST	Burst Stop → Bank Active (BL=Full Column) NOP (BL=1, 2, 4, 8)	
	L	Н	L	Н	BA, CA, AP	READ/READA	Terminate Burst, New Read; Determine AP	
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Terminate Burst, Start Write; Determine AP	*4
	L	L	Н	Н	BA, RA	ACTV	Illegal	*2
	L	L	Н	L	BA, AP	PRE/PALL	Terminate Burst, Precharge; Determine Precharge Type	
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	
Write	Н	х	Х	Х	Х	DESL	NOP (Continue Burst to End → Write Recovering)	
	L	Н	Н	Н	X	NOP	NOP (Continue Burst to End → Write Recovering)	
	L	Н	Н	L	х	BST	Burst Stop → Write Recovering → Bank Active (BL=Full Column) NOP(BL=1, 2, 4, 8)	
	L	Н	L	Н	BA, CA, AP	READ/READA	Terminate Burst, Start Read; Determine AP	
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Terminate Burst, New Write; Determine AP	*4
	L	L	Н	Н	BA, RA	ACTV	Illegal	*2
	L	L	Н	L	BA, AP	PRE/PALL	Terminate Burst, Precharge; Determine Precharge Type	*4
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	

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Current State	CS	RAS	CAS	WE	Addr	Command	Function	Notes
Read with Auto- Precharge	Н	х	х	Х	Х	DESL	NOP (Continue Burst to End → Precharge)	
Frecharge	L	Н	Н	Н	х	NOP	NOP (Continue Burst to End → Precharge)	
	L	Н	Н	L	Х	BST	Illegal	
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal	*2
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal	*2
	L	L	Н	Н	BA, RA	ACTV	Other Bank Active, Illegal on Same Bank	*2
	L	L	Н	L	BA, AP	PRE/PALL	Illegal	*2
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	
Write with Auto- Precharge	Н	х	Х	Х	Х	DESL	NOP (Continue Burst to End → Write Recovering with Precharge)	
riecharge	L	Н	Н	Н	Х	NOP	NOP (Continue Burst to End → Write Recovering with Precharge)	
	L	Н	Н	L	Х	BST	Illegal	
	L	Н	L	Н	BA, CA, AP	READ/READA	Other Bank Read, Illegal on Same Bank	*2
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Other Bank Write, Illegal on Same Bank	*2
	L	L	Н	Н	BA, RA	ACTV	Illegal	*2
	L	L	Н	L	BA, AP	PRE/PALL	Illegal	*2
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	

Current State	cs	RAS	CAS	WE	Addr	Command	Function No.	otes
Precharge	Н	Х	Х	Х	Х	DESL	NOP (Idle after trp)	
	L	Н	Н	Н	Х	NOP	NOP (Idle after trp)	
	L	Н	Н	L	Х	BST	Illegal	
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal	*2
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal	*2
	L	L	Н	Н	BA, RA	ACTV	Illegal	*2
	L	L	Н	L	BA, AP	PRE/PALL	NOP (PALL May Affect Other Bank)	*5
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	
Bank Activating	Н	Х	Х	Х	Х	DESL	NOP (Bank Active after trcd)	
Activating	L	Н	Н	Н	Х	NOP	NOP (Bank Active after trcd)	
	L	Н	Н	L	Х	BST	NOP (Bank Active after trcd)	
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal	*2
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal	*2
	L	L	Н	Н	BA, RA	ACTV	Illegal	*6
	L	L	Н	L	BA, AP	PRE/PALL	Illegal	*2
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	

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Current State	CS	RAS	CAS	WE	Addr	Command	Function	Notes
Write Recovering	Н	Х	Х	Х	Х	DESL	NOP (Bank Active after twr/tbwc)	
Recovering	L	Н	Н	Н	Х	NOP	NOP (Bank Active after twr/tbwc)	
	L	Н	Н	L	Х	BST	NOP (Bank Active after twr/tbwc)	
	L	Н	L	Н	BA, CA, AP	READ/READA	Start Read; Determine AP	*4
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	New Write; Determine AP	
	L	L	Н	Н	BA, RA	ACTV	Illegal	*2
	L	L	Н	L	BA, AP	PRE/PALL	Illegal	*2
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	
Write Recovering	Н	Х	Х	X	Х	DESL	NOP (Precharge after trwt/tbwt)	
with Auto-	L	Н	Н	Н	Х	NOP	NOP (Precharge after trwt/tbwt)	
Precharge	L	Н	Н	L	Х	BST	Illegal	
	L	Н	L	Н	BA, CA, AP	READ/READA	Illegal	*2
	L	Н	L	L	BA, CA, AP	WRIT/WRITA	Illegal	*2
	L	L	Н	Н	BA, RA	ACTV	Illegal	*2
	L	L	Н	L	BA, AP	PRE/PALL	Illegal	*2
	L	L	L	Н	Х	REF/SELF	Illegal	
	L	L	L	L	MODE	MRS	Illegal	

(Continued)

Current State	cs	RAS	CAS	WE	Addr	Command	Function Notes
Refreshing	Н	Х	Х	Х	Х	DESL	NOP (Idle after t _{RC})
	L	Н	Н	Х	Х	NOP/BST	NOP (Idle after t _{RC})
	L	Н	L	Х	Х	READ/READA/ WRIT/WRITA	Illegal
	L	L	Н	Х	Х	ACTV/PRE/ PALL	Illegal
	L	L	L	Х	Х	REF/SELF/ MRS	Illegal *6
Mode Register	Н	Х	Х	Х	Х	DESL	NOP (Idle after trsc)
Setting	L	Н	Н	Н	Х	NOP	NOP (Idle after trsc)
	L	Н	Н	L	Х	BST	Illegal
	L	Н	L	х	Х	READ/READA/ WRITWRITA	Illegal
	L	L	х	х	Х	ACTV/PRE/ PALL/REF/ SELF/MRS	Illegal

ABBREVIATIONS:

RA = Row Address
CA = Column Address
AP = Auto Precharge

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COMMAND TRUTH TABLE FOR CKE

Current State	CKE n-1	CKE n	cs	RAS	CAS	WE	Addr	Function Notes
Self Refresh	Н	Х	Х	Х	Х	Х	Х	Invalid
	L	Н	Н	Х	Х	Х	Х	Exit Self Refresh, Idle after tRC
	L	Н	L	Н	Н	Н	Х	Exit Self Refresh, Idle after tRC
	L	Н	L	Н	L	Х	Х	Illegal
	L	Н	L	L	Х	Х	Х	Illegal
	L	L	Х	Х	Х	Х	Х	NOP (Maintain Self Refresh)
Self Refresh Recovery	Н	Н	Н	Х	Х	Х	Х	Idle after tec
Recovery	Н	Н	L	Н	Н	Х	Х	Idle after tec
	Н	Н	L	Н	L	Х	Х	Illegal
	Н	Н	L	L	Х	Х	Х	Illegal
	Н	L	Н	Х	Х	Х	Х	Begin Clock Suspend Next Cycle
	Н	L	L	Н	Н	Х	Х	Begin Clock Suspend Next Cycle
	Н	L	L	Н	L	Х	Х	Illegal
	Н	L	L	L	Х	Х	Х	Illegal
	L	Н	Х	Х	Х	Х	Х	Exit Clock Suspend Next Cycle
	L	L	Х	Х	Х	Х	Х	Maintain Clock Suspend

Current State	CKE n-1	CKE n	cs	RAS	CAS	WE	Addr	Function Notes
Power Down	Н	Х	Х	Х	Х	Х	_	Invalid
Down			Н	Х	Х	Х	Х	Cuit Dawer Dawe Mada Lidla
	L	Н	L	Н	Н	Н	Х	Exit Power Down Mode → Idle
	L	L	Х	Х	Х	Х	Х	NOP (Maintain Power Down Mode)
	L	Н	L	L	Х	Х	Х	Illegal
	L	Н	L	Н	L	Х	Х	Illegal
Both Banks	Н	Н	Н	Х	Х	Х	_	Refer to the Operation Command Table
Idle	Н	Н	L	Н	Х	Х	_	Refer to the Operation Command Table
	Н	Н	L	L	Н	Х	_	Refer to the Operation Command Table
	Н	Н	L	L	L	Н	Х	Auto Refresh
	Н	Н	L	L	L	L	SPECIAL MODE	Refer to the Operation Command Table
	Н	Н	L	L	L	L	MODE	Refer to the Operation Command Table
	Н	L	Н	Х	Х	Х		Refer to the Operation Command Table
	Н	L	L	Н	Х	Х		Refer to the Operation Command Table
	Н	L	L	L	Н	Х		Refer to the Operation Command Table
	Н	L	L	L	L	Н	Х	Self Refresh
	Н	L	L	L	L	L	SPECIAL MODE	Refer to the Operation Command Table
	Н	L	L	L	L	L	MODE	Refer to the Operation Command Table
	L	Х	Х	Х	Х	Х	X	Power Down

(Continued)

Current State	CKE n-1	CKE n	CS	RAS	CAS	WE	Addr	Function Notes			
Bank Active Bank	Н	Н	Х	Х	Х	Х	Х	Refer to the Operation Command Table			
Activating Read/Write	Н	L	Х	Х	Х	Х	Х	Begin Clock Suspend Next Cycle			
Tread, Trite	L	Н	Х	Х	Х	Х	Х	Exit Clock Suspend Next Cycle			
	L	L	Х	Х	Х	Х	Х	Maintain Clock Suspend			
Clock	Н	Х	Х	Х	Х	Х	Х	Invalid			
Suspend	L	Н	Х	Х	Х	Х	Х	Exit Clock Suspend Next Cycle			
	L	L	Х	Х	Х	Х	Х	Maintain Clock Suspend			
Any State Other Than	Н	Н	Х	Х	Х	Х	Х	Refer to the Operation Command Table			
Listed Above	Н	L	Х	Х	Х	Х	Х	Begin Clock Suspend Next Cycle			
	L	Н	Х	Х	Х	Х	Х	Exit Clock Suspend Next Cycle			
	L	L	Х	Х	Х	Х	X	Maintain Clock Suspend			

Notes: *1. All entries assume the CKE was High during the proceeding clock cycle and the current clock cycle.

- *2. Illegal to bank in specified state; entry may be legal in the bank specified by BA, depending on the state of that bank.
- *3. Illegal if any bank is not idle.
- *4. Must satisfy bus contention, bus turn around, and/or write recovery requirements.
- *5. NOP to bank precharging or in idle state. May precharge bank spesified by BA (and AP).
- *6. trrd must be satisfied for other bank.

■ FUNCTIONAL DESCRIPTION

SDRAM BASIC FUNCTION

Three major differences between this SDRAM and conventional DRAMs are:synchronized operation, burst mode, and mode register.

The **synchronized operation** is the fundamental difference. An SDRAM uses a clock input for the synchronization, where the DRAM is basically asynchronous memory although it has been using two clocks, RAS and CAS. Each operation of DRAM is determined by their timing phase differences while each operation of SDRAM is determined by commands and all operations are referenced to a positive clock edge. Fig. 3 shows the basic timing diagram differences between SDRAMs and DRAMs.

The **burst mode** is a very high speed access mode utilizing an internal column address generator. Once a column addresses for the first access is set, following addresses are automatically generated by the internal column address counter.

The **mode register** is to justify the SDRAM operation and function into desired system conditions. MODE REGISTER TABLE shows how SDRAM can be configured for system requirement by mode register programming.

CLOCK (CLK) AND CLOCK ENABLE (CKE)

All input and output signals of SDRAM use register type buffers. A CLK is used as a trigger for the register and internal burst counter increment. All inputs are latched by a positive edge of CLK. All outputs are validated by the CLK. CKE is a high active clock enable signal. When CKE = Low is latched at a clock input during active cycle, the next clock will be internally masked. During idle state (all banks have been precharged), the Power Down mode(standby) is entered with CKE = Low and this will make extremely low standby current.

CHIP SELECT (CS)

 $\overline{\text{CS}}$ enables all commands inputs, $\overline{\text{RAS}}$, $\overline{\text{CAS}}$, and $\overline{\text{WE}}$, and address input. When $\overline{\text{CS}}$ is High , command signals are negated but internal operation such as burst cycle will not be suspended. If such a control isn't needed, $\overline{\text{CS}}$ can be tied to ground level.

COMMAND INPUTS (RAS, CAS AND WE)

Unlike a conventional DRAM, \overline{RAS} , \overline{CAS} , and \overline{WE} do not directly imply SDRAM operation, such as Row address strobe by \overline{RAS} . Instead, each combination of \overline{RAS} , \overline{CAS} , and \overline{WE} input in conjunction with \overline{CS} input at a rising edge of the CLK determines SDRAM operation. Refer to FUNCTION TRUTH TABLE in page 5.

ADDRESS INPUTS (Ao to A10)

Address input selects an arbitrary location of a total of 2,097,152 words of each memory cell matrix. A total of twenty address input signals are required to decode such a matrix. SDRAM adopts an address multiplexer in order to reduce the pin count of the address line. At a Bank Active command (ACTV), eleven Row addresses are initially latched and the remainder of ten column addresses are then latched by a column address strobe command of either a Read command (READ or READA) or Write command (WRIT or WRITA).

BANK SELECT (A11)

This SDRAM has two banks and each bank is organized as 2 M words by 4-bit.

Bank selection by A₁₁ occurs at Bank Active command (ACTV) followed by Read (READ or READA), Write (WRIT or WRITA), and Precharge command (PRE).

DATA INPUTS AND OUTPUTS (DQ0 to DQ3)

Input data is latched and written into the memory at the clock following the Write command input. Data output is obtained by the following conditions followed by a Read command input:

trac: from the bank Active command when trop (min) is satisfied. (This parameter is reference only.)

tcac: from the Read command when tRCD is greater than tRCD (min).

tac: from the clock edge after trac and toac.

The polarity of the output data is identical to that of the input. Data is valid between access time (determined by the three conditions above) and the next positive clock edge (toh).

DATA I/O MASK (DQM)

DQM is an active high enable input and has an output disable and input mask function. During burst cycle and when DQM = High is latched by a clock, input is masked at the same clock and output will be masked at the second clock later while internal burst counter will increment by one or will go to the next stage depending on burst type.

BURST MODE OPERATION AND BURST TYPE

The burst mode provides faster memory access. The burst mode is implemented by keeping the same Row address and by automatic strobing column address. Access time and cycle time of Burst mode is specified as tac and tok, respectively. The internal column address counter operation is determined by a mode register which defines burst type and burst count length of 1,2 or 4 bits of boundary. In order to terminate or to move from the current burst mode to the next stage while the remaining burst count is more than 1, the following combinations will be required:

Current Stage	Next Stage	М	ethod (Assert the following command)					
Burst Read	Burst Read	Read Commar	nd					
Burst Read	Burst Write	1st Step	Mask Command (Normally 3 clock cycles)					
Buist Read	Burst Read Burst Write		Write Command after lowd					
Burst Write	Burst Write	Write Commar	nd					
Burst Write	Burst Read	Read Commar	nd					
Burst Read	Precharge	Precharge Cor	Precharge Command					
Burst Write	Precharge	Precharge Cor	mmand					

The burst type can be selected either sequential or interleave mode if burst length is 2 or 4. The sequential mode is an incremental decoding scheme within a boundary address to be determined by count length, it assigns +1 to the previous (or initial) address until reaching the end of boundary address and then wraps round to least significant address(=0). The interleave mode is a scrambled decoding scheme for A_0 and A_2 . If the first access of column address is even (0), the next address will be odd (1), or vice-versa.

BURST MODE OPERATION AND BURST TYPE (continued)

When the full burst operation is executed at single write mode, Auto-precharge command is valid only at write operation.

The burst type can be selected either sequential or interleave mode. But only the sequential mode is usable to the full column burst. The sequential mode is an incremental decoding scheme within a boundary address to be determined by burst length, it assigns +1 to the previous (or initial) address until reaching the end of boundary address and then wraps round to least significant address(=0).

Burst Length	Stating Column Address A ₂ A ₁ A ₀	Sequential Mode	Interleave
2	X X 0	0 - 1	0 - 1
	X X 1	1 - 0	1 - 0
	X 0 0	0 - 1 - 2 - 3	0 - 1 - 2 - 3
4	X 0 1	1 - 2 - 3 - 0	1 - 0 - 3 - 2
4	X 1 0	2 - 3 - 0 - 1	2 - 3 - 0 - 1
	X 1 1	3 - 0 - 1 - 2	3 - 2 - 1 - 0
	0 0 0	0 - 1 - 2 - 3 - 4 - 5 - 6 - 7	0 - 1 - 2 - 3 - 4 - 5 - 6 - 7
	0 0 1	1 - 2 - 3 - 4 - 5 - 6 - 7 - 0	1 - 0 - 3 - 2 - 5 - 4 - 7 - 6
	0 1 0	2 - 3 - 4 - 5 - 6 - 7 - 0 - 1	2 - 3 - 0 - 1 - 6 - 7 - 4 - 5
8	0 1 1	3 - 4 - 5 - 6 - 7 - 0 - 1 - 2	3 - 2 - 1 - 0 - 7 - 6 - 5 - 4
0	1 0 0	4 - 5 - 6 - 7 - 0 - 1 - 2 - 3	4 - 5 - 6 - 7 - 0 - 1 - 2 - 3
	1 0 1	5 - 6 - 7 - 0 - 1 - 2 - 3 - 4	5 - 4 - 7 - 6 - 1 - 0 - 3 - 2
	1 1 0	6 - 7 - 0 - 1 - 2 - 3 - 4 - 5	6 - 7 - 4 - 5 - 2 - 3 - 0 - 1
	1 1 1	7 - 0 - 1 - 2 - 3 - 4 - 5 - 6	7 - 6 - 5 - 4 - 3 - 2 - 1 - 0

FULL COLUMN BURST AND BURST STOP COMMAND (BST)

The full column burst is an option of burst length and available only at sequential mode of burst type. This full column burst mode is repeatedly access to the same column. If burst mode reaches end of column address, then it wraps round to first column address (=0) and continues to count until interrupted by the news Read (READ) /Write (WRIT/BWRIT), Precharge (PRE), or Burst stop (BST) command. The selection of autoprecharge option is illegal during the full column burst operation except Write command at BURST READ & SINGLE WRITE mode.

The BST command is applicable to terminated the full column burst operation and illegal during the burst operation with length of 1, 2, 4, and 8. If the BST command is asserted during the full column burst mode, its operation is terminated immediately and the internal state moves to Bank Active.

When read mode is interrupted by BST command, the output will be in High-Z.

For the detail rule, please refer to TIMING DIAGRAM-8.

When write mode is interrupted by BST command, the data to be applied at the same time with BST command will be ignored.

BURST READ & SINGLE WRITE

The burst read and single write mode provides single word write operation regardless of its burst length. In this mode, burst read operation does not be affected by this mode.

PRECHARGE AND PRECHARGE OPTION (PRE, PALL)

SDRAM memory core is the same as conventional DRAMs', requiring precharge and refresh operations. Precharge rewrites the bit line and to reset the internal Row address line and is executed by the Precharge command (PRE). With the Precharge command, SDRAM will automatically be in standby state after precharge time (trp).

The precharged bank is selected by combination of AP and A₁₁ when Precharge command is asserted. If AP = High, both banks are precharged regardless of A₁₁ (PALL). If AP = Low, a bank to be selected by A₁₁ is precharged (PRE). The auto-precharge enters precharge mode at the end of burst mode of read or write without Precharge command assertion. This auto precharge is entered by AP=High when a Read or Write command is asserted. Refer to FUNCTION TRUTH TABLE.

AUTO-REFRESH (REF)

Auto-refresh uses the internal refresh address counter. The SDRAM Auto-refresh command (REF) generates Precharge command internally. All banks of SDRAM should be precharged prior to the Auto-refresh command. The Auto-refresh command should also be asserted every 16 μs or a total 2048 refresh commands within a 32.8 ms period.

SELF-REFRESH ENTRY (SELF)

Self-refresh function provides automatic refresh by an internal timer as well as Auto-refresh and will continue the refresh function until cancelled by SELFX.

The Self-refresh is entered by applying an Auto-refresh command in conjunction with CKE = Low (SELF). Once SDRAM enters the Self-refresh mode, all inputs except for CKE will be "don't care" (either logic high or low level state) and outputs will be in a High-Z state. During a Self-refresh mode, CKE = Low should be maintained. SELF command should only be issued after last read data has been appeared on DQ.

SELF-REFRESH EXIT (SELFX)

To exit Self-refresh mode, apply minimum 4 clock cycles before CKE brought high, and then the NOP command (NOP) or the Deselect command (DESL) should be asserted within one tRC period. CKE should be held High within one tRC period after tPDE. Refer to Timing Diagram for the detail.

It is recommended to assert an Auto-refresh command just after the t_{RC} period to avoid the violation of refresh period.

MODE REGISTER SET (MRS)

The mode register of SDRAM provides a variety of different operations. The register consists of four operation fields; Burst Length, Burst Type, CAS latency, and Operation Code. Refer to MODE REGISTER TABLE in page 32.

The mode register can be programmed by the Mode Register Set command (MRS). Each field is set by the address line. Once a mode register is programmed, the contents of the register will be held until re-programmed by another MRS command (or part loses power). MRS command should only be issued on condition that all DQ is in Hi-Z.

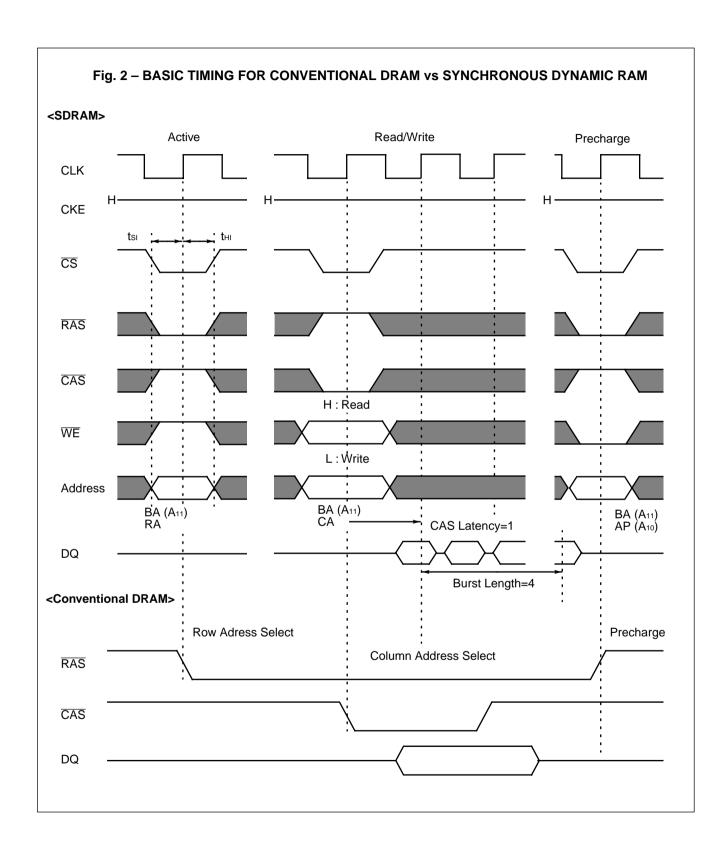
The condition of the mode register is undefined after the power-up stage. It is required to set each field after initialization of SDRAM. Refer to POWER-UP INITIALIZATION below.

POWER-UP INITIALIZATION

The SDRAM internal condition after power-up will be undefined. It is required to follow the following Power On Sequence to execute read or write operation.

- 1. Apply power and start clock. Attempt to maintain either NOP or DESL command at the input.
- 2. Maintain stable power, stable clock, and NOP condition for a minimum of 200 μs.
- 3. Precharge all banks by Precharge (PRE) or Precharge All command (PALL).
- 4. Assert minimum of 8 Auto-refresh command(REF).
- 5. Program the mode register by Mode Register Set command(MRS).

In addition, it is recommended DQM and CKE to track Vcc to insure that output is High-Z state. The Mode Register Set command (MRS) can be set before 8 Auto-refresh command (REF).

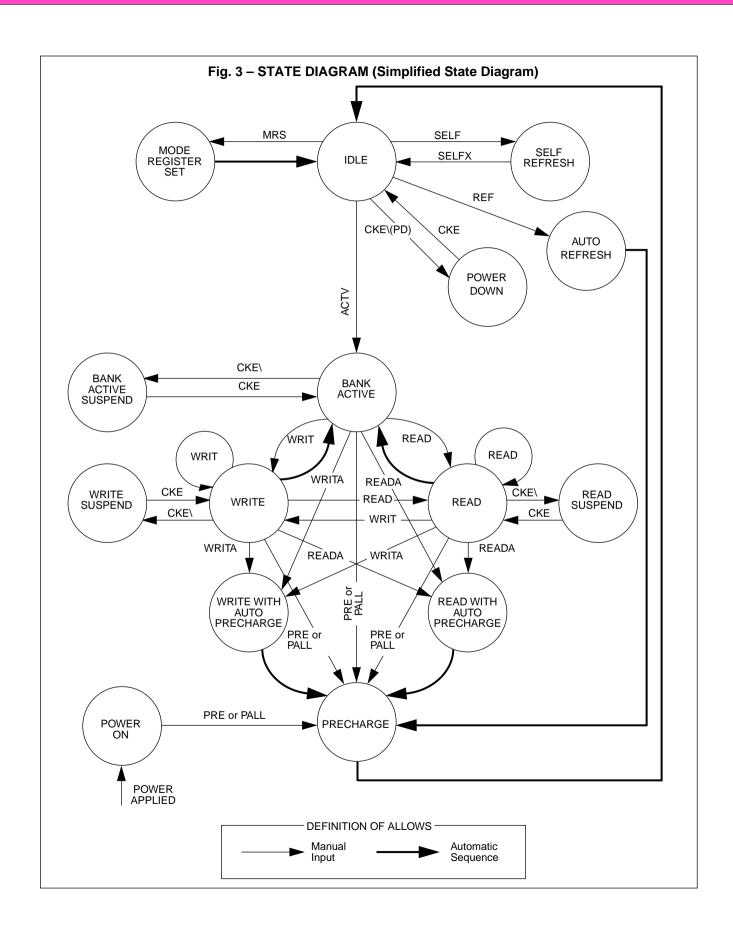


CLOCK LATENCY OR DELAY TIME FOR 2 BANK OPERATION

Second command (opposite bank) First command	MRS	ACTV	READ	READ A	WRT	WRITA	PRE	PALL	REF	SELF
MRS	I MRD	Imrd							I MRD	I MRD
ACTV		*1 t RRD	1	*2 1	*2 1	*2 1	1	t ras		
READ		*1 1	*2 1	*2 1	*2 *3 1	*2 *3 1	1	1		
READA		*1 1	1	1	*2 *3	*2 *3 1	1	1	*1 BL + t _{RP}	*1 BL + t _{RP}
WRIT		*1 1	*2 1	1	*2 1	1	1	1		
WRITA		*1 1	1	1	*2 1	1	1	1	BL + 1 + t _{RP}	BL + 1 + t _{RP}
PRE	*1 t RP	*1 1	*2 1	1	*2 1	1	1	1	*1 t RP	*1 t RP
PALL *5	t RP	*1 1					1	1	*1 *6 t RP	*1 *6 t RP
REF	t RC	trc						_	trrd	t RC
SELF	tPDE + trc	tPDE + trc							tpde + trc	tpde + trc

Notes: *1. Assume opposite bank is in idle state.

- *2. Assume opposite bank is in active state.
- *3. Assume no I/O conflict.
- *4. If $t_{RP} \leftarrow t_{CK}$, minimum latency is a sum of BL + CL.
- *5. Assume PALL command dose not affect any operation on opposite bank.
- *6. Assume Output is in High-Z state.



■ ABSOLUTE MAXIMUM RATINGS (See WARNING)

Parameter	Symbol	Value	Unit
Voltage of Vcc Supply Relative to Vss	Vcc, Vccq	-0.5 to +4.6	V
Voltage at Any Pin Relative to Vss	VIN, VOUT	-0.5 to +4.6	V
Short Circuit Output Current	louт	±50	mA
Power Dissipation	Po	1.3	W
Storage Temperature	Тѕтс	-55 to +125	°C

WARNING: Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

■ RECOMMENDED OPERATING CONDITIONS

(Referenced to Vss)

Parameter	Notes	Symbol	Min.	Тур.	Max.	Unit
Supply Voltage		Vcc, Vccq	3.0	3.3	3.6	V
Supply Voltage		Vss, Vssq	0	0	0	V
Input High Voltage	*1	VIH	2.0	_	Vcc + 0.5	V
Input Low Voltage	*2	VIL	-0.5	_	0.8	V
Ambient Temperature		TA	0	_	70	°C

Notes: *1. Overshoot limit : V_{IH}(max)= TBD.

*2. Undershoot limit: $V_{LL}(min) = -1.5 \text{ V}$ with a pullsewidth $\leq 5 \text{ ns}$.

WARNING: Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representative beforehand.

■ CAPACITANCE

 $(T_A = 25^{\circ}C, f = 1 \text{ MHz})$

Parameter	Symbol	Тур.	Max.	Unit
Input Capacitance, Address	C _{IN1}	_	4	pF
Input Capacitance, Except for address	C _{IN2}	_	4	pF
I/O Capacitance	C _{I/O}	_	7	pF

■ DC CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.) Notes 1, 2

Doro	meter	Symbol	Conditions	Va	lue	Unit
Pala	imeter	Symbol	Conditions	Min.	Max.	Unit
Output High Voltage		V _{OH(DC)}	Iон = −2 mA	2.4	_	V
Output Low Voltage		Vol(DC)	IoL = 2 mA	_	0.4	V
Input Leakage Curre	nt (Any Input)	lu	$0 \text{ V} \le \text{V}_{\text{IN}} \le \text{V}_{\text{CC}};$ All other pins not under test = 0 V	-10	10	μА
Output Leakage Curr	rent	ILO	0 V ≤ V _{IN} ≤ V _{CC} ; Data out disabled	-10	10	μА
	MB81117422A-125		No Burst:		90	
	MB81117422A-100	lcc1s	tck = min trc = min		85	mA
O	MB81117422A-84	ICC1S	One bank active	_	80	IIIA
Operating Current	MB81117422A-67		0 V ≤ VIN ≤ Vcc		75	
(Average Power Supply Current)	MB81117422A-125		No Burst:		140	
	MB81117422A-100	Icc1D	tck = min trc = min		130	mA
	MB81117422A-84	ICC1D	All banks active	_	120	IIIA
	MB81117422A-67		0 V ≤ VIN ≤ Vcc		110	
Precharge Standby C		Ісс2Р	$ \begin{array}{l} CKE = V_{IL} \\ All \ banks \ idle \\ t_{CK} = min \\ Power \ down \ mode \\ 0 \ V \leq V_{IN} \leq V_{CC} \\ \end{array} $		2	mA
(Power Supply Curre	nt)	ICC2N	$ CKE = V_{IH} $ All banks idle $ t_{CK} = min $ $ 0 \ V \le V_{IN} \le V_{CC} $	_	2	
Active Standby Curre	ent	Іссзр	$ CKE = V_{IL} $ Any bank active $ t_{CK} = min $ $ 0 \ V \le V_{IN} \le V_{CC} $	_	30	mA
(Power Supply Curre		Іссзи	$ CKE = V_{IH} $	_	50	mA
Durat Mada	MB81117422A-125				150	mA
Burst Mode Current	MB81117422A-100	1.	tck = min		135	
(Average Power	MB81117422A-84	Icc4	0 V ≤ VIN ≤ VCC	_	125	
Supply Current)	MB81117422A-67	1			115	

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Poror	Parameter		Conditions	Va	Unit	
r ai aifletei		Symbol	Conditions	Min.	Min. Max.	
Refresh Current #1	MB81117422A-125		Auto Refresh;		120	
	MB81117422A-100	lcc5	tck = min		110	mA
(Average Power Supply Current)	MB81117422A-84		trc = min trrd = min	_	100	
Cupply Culture,	MB81117422A-67		0 V ≤ VIN ≤ VCC		90	
Refresh Current #2 (Average Power Supply Current)		Icc ₆		_	2	mA

■ AC CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.) Notes 2, 3, 4

Paramete	Parameter Notes			17422A 25		17422A 00		17422A 34		17422A 57	Unit
		Symbol	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Clock Period	CAS latency=2	t cĸ	12		15		17		20		ns
Clock Period	CAS latency=3	lCK	8	_	10	_	12		15	_	ns
Clock High Time		tсн	3.5	_	4	_	4	_	4	_	ns
Clock Low Time		t cL	3.5	_	4	_	4	_	4	_	ns
Input Set Up Time		t sı	3	_	3	_	3	_	3	_	ns
Input Hold Time		tнı	1	_	1	_	1	_	1	_	ns
Access Time	CAS latency=2	_		9		9		9		10	ns
from Clock (tck=min) *5,6	CAS latency=3	t ac	_	7.5	_	8.5	_	8.5	_	9	ns
Output in Low-Z		tolz	2	_	3	_	3	_	3	_	ns
Output in High-Z	*7	t onz	2	_	3	_	3	_	3	_	ns
Output Hold Time		tон	2	_	3	_	3	_	3	_	ns
Time between Refresh		t REF	_	32.8	_	32.8	_	32.8	_	32.8	ms
Transition Time		t ⊤	0.5	2	0.5	2	0.5	2	0.5	2	ns
Power Down Exit	Time	t PDE	3	_	3	_	4	_	5	_	ns

BASE VALUES FOR CLOCK COUNT/LATENCY

Parameter	Notes	Symbol		17422A 25	MB81117422A -100		MB81117422A -84		MB81117422A -67		Unit
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
RAS Cycle Time	*8	trc	75	_	90	_	100	_	110	_	ns
RAS Access Time	*9	t RAC	_	45	_	54	_	56	_	60	ns
CAS Access Time	*10,13	tcac	_	21	_	24	_	26	_	30	ns
RAS Precharge Time		t RP	27	_	30	_	35	_	40	_	ns
RAS Active Time		t ras	48	10000 0	60	10000	65	10000 0	70	10000	ns
RAS to CAS Delay Time	*11	t RCD	24	_	30	_	30	_	30	_	ns
Write Recovery Time		t wr	8	_	10	_	12	_	15	_	ns
Write to Precharge Delay T	ime	t RWL	8	_	10	_	12	_	15	_	ns
RAS to RAS Bank Active D	elay	t rrd	24	_	30	_	30	_	30	_	ns

CLOCK COUNT FORMULA Note13

$${\sf Clock} \geq \frac{{\sf Base \, Value}}{{\sf Clock \, Period}} \quad ({\sf Round \, off \, a \, whole \, number})$$

LATENCY-FIXED VALUES

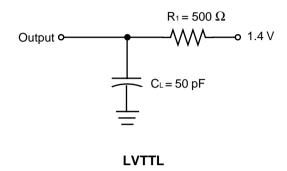
(The latency values on these parameters are fixed regardless of clock period.)

Parameter	Notes	Symbol	MB81117422A -125	MB81117422A -100	MB81117422A -84	MB81117422A -67	Unit
CKE to Clock Disable		Іске	1	1	1	1	cycle
DQM to Output in High-Z		ldQz	2	2	2	2	cycle
DQM to Input Data Delay		IDQD	0	0	0	0	cycle
Last Output to Write Command Delay		lowd	2	2	2	2	cycle
Write Command to Input Data Delay		lowd	0	0	0	0	cycle
Precharge to Output in High-Z Delay	CL = 2	Ггон	2	2	2	2	cycle
	CL = 3		3	3	3	3	cycle
Burst Stop Command to Output in High-Z Delay	CL = 2	- Івѕн	2	2	2	2	cycle
	CL = 3		3	3	3	3	cycle
Mode Register Access to Banks Active		I MRD	2	2	2	2	cycle
CAS to CAS Delay (min)		Iccd	1	1	1	1	cycle
CAS Bank Delay (min)		Ісво	1	1	1	1	cycle

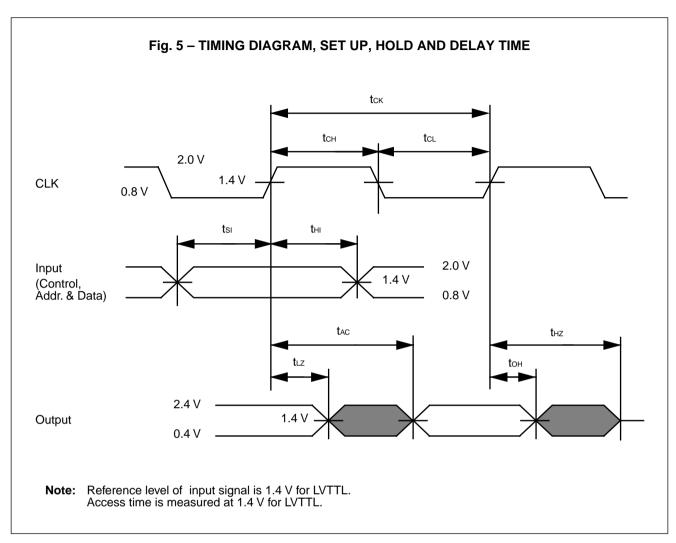
Notes: *1. lcc depends on the output termination or load conditions, clock cycle rate, and signal clocking rate; The specified values are obtained with the output open and no termination register.

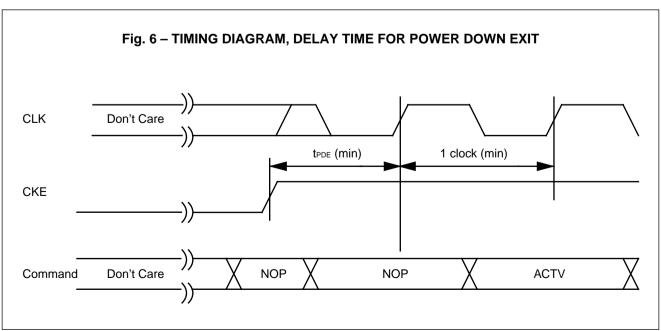
- *2. An initial pause (DESL or NOP) of 200 μs is required after power-up followed by a minimum of eight Auto-refresh cycles.
- *3. AC characteristics assume $t_T = 1$ ns and 30 pF of capacitive load.
- *4. 1.4 V is the reference level for measuring timing of input signals. Transition times are measured between V_{IH} (min) and V_{IL} (max).
- *5. Assumes tRCD and tCAC are satisfied.
- *6. tac also specifies the access time at burst mode except for first access.
- *7. Specified where output buffer is no longer driven.
- *8. Actual clock count of tre (Irc) will be sum of clock count of tras (Iras) and trp (Irp).
- *9. trac is a reference value. Maximum value is obtained from the sum of trac (min) and toac (max).
- *10. Assumes trac and tac are satisfied.
- *11. Operation within the trcd (min) ensures that trac can be met; if trcd is greater than the specified trcd (min), access time is determined by tcac or tac.
- *12. All base values are measured from the clock edge at the command input to the clock edge for the next command input. All clock counts are calculated by a simple formula: clock count equals base value divided by clock period (round off to a whole number).
- *13. The tcac is programmed by the mode register.

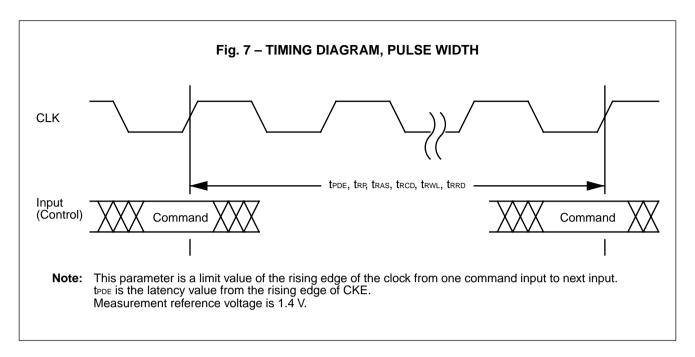
Fig. 4 – EXAMPLE OF AC TEST LOAD CIRCUIT

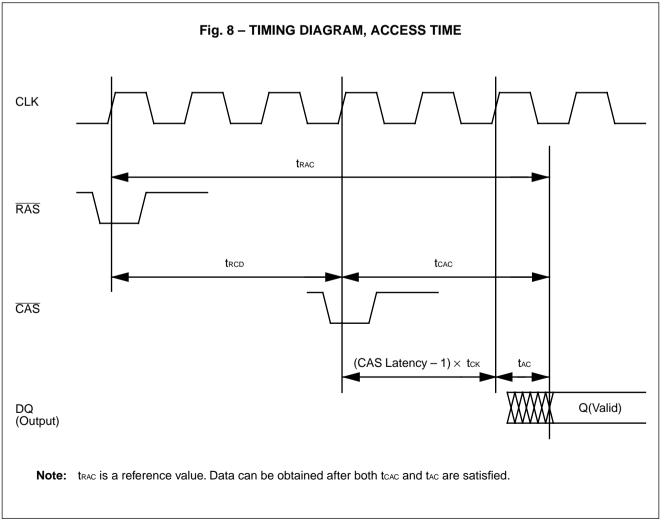


Note: AC characteristics are measured in this condition. This load circuits are not applicable for Voh and Vol.

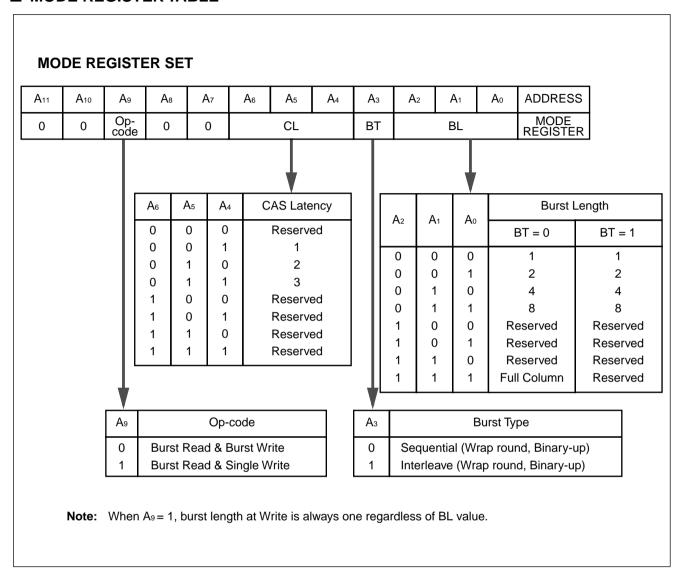


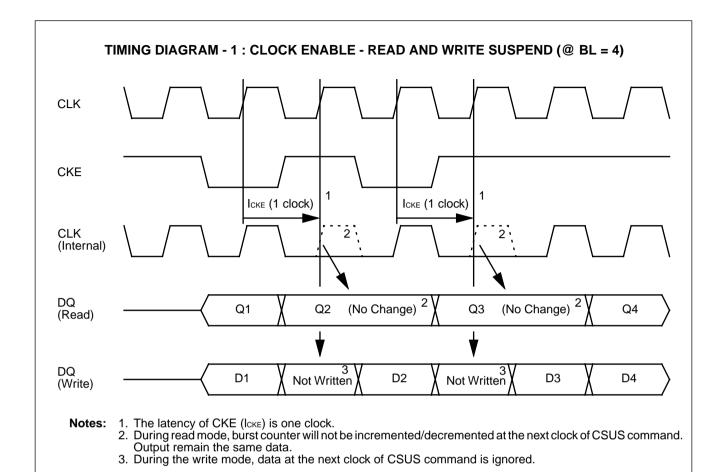


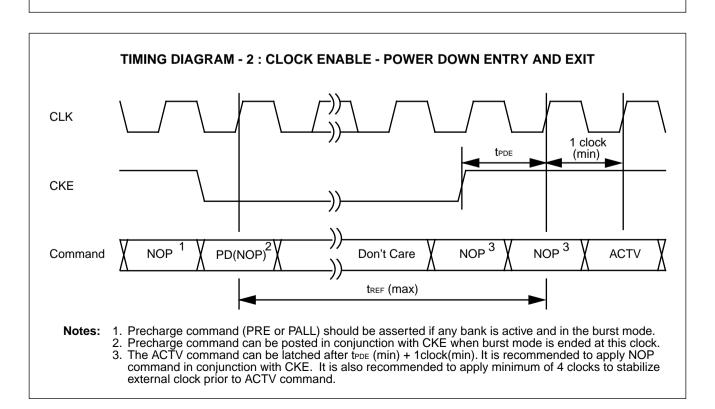


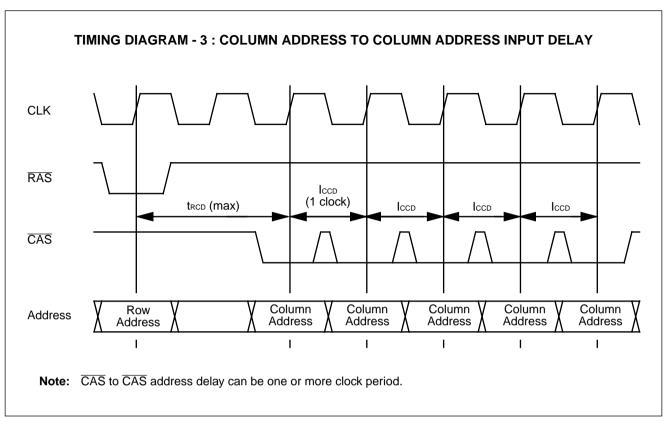


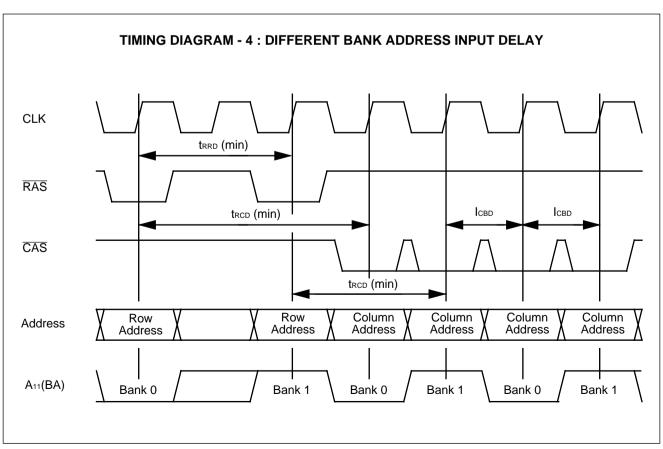
■ MODE REGISTER TABLE

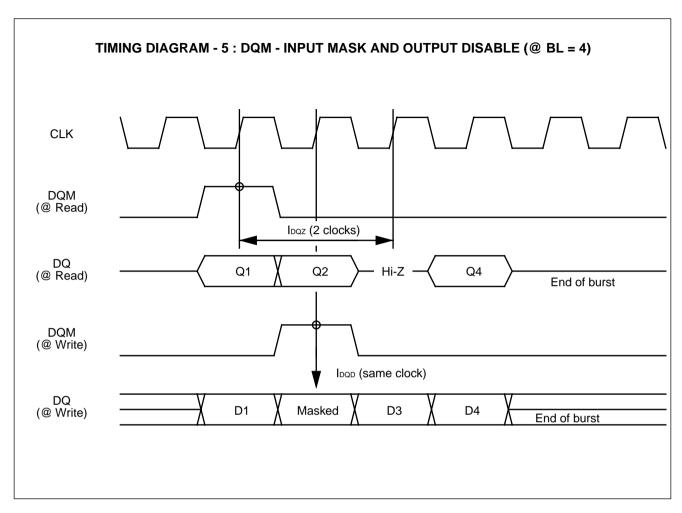


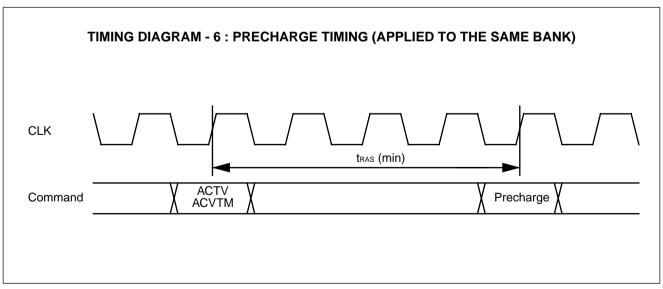


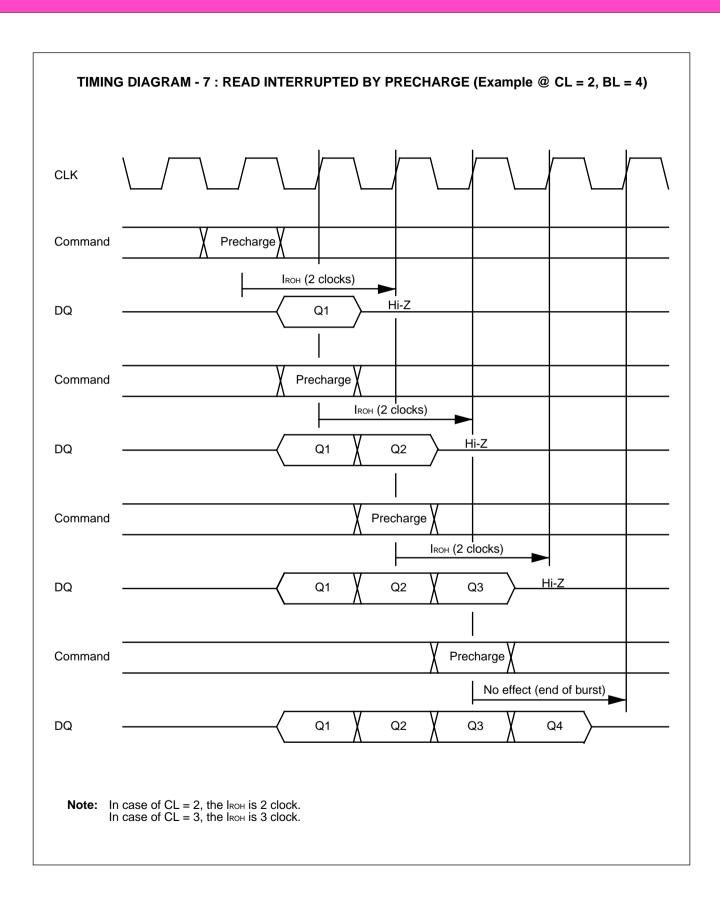


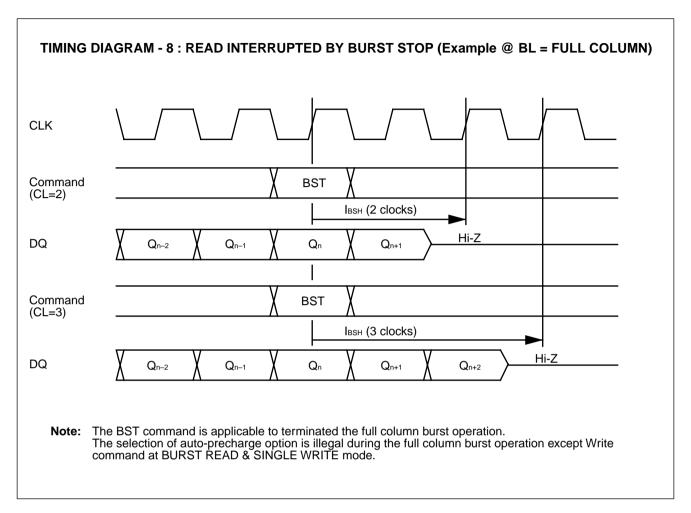


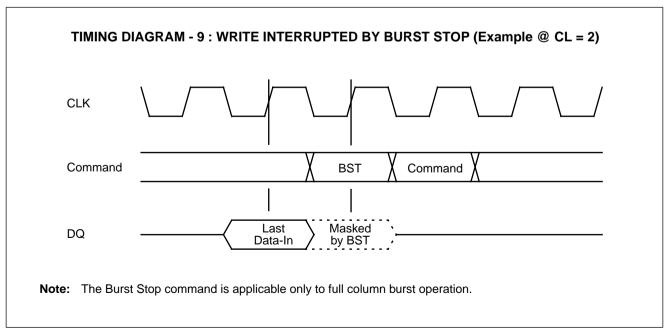


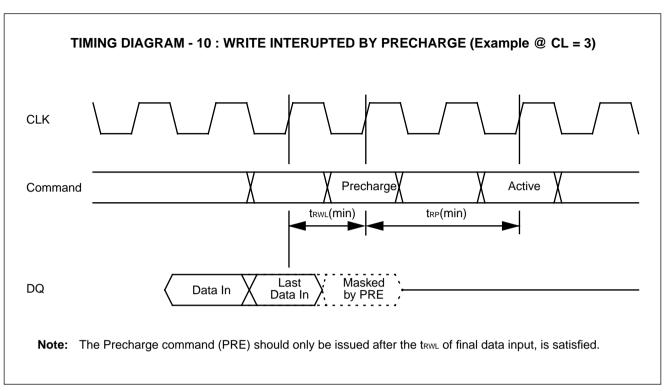


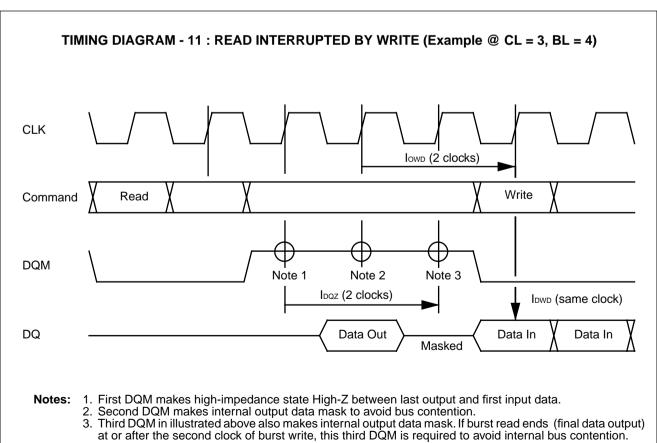




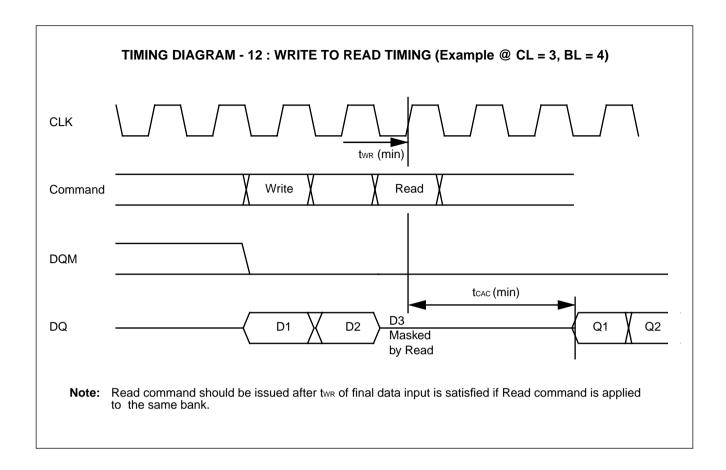


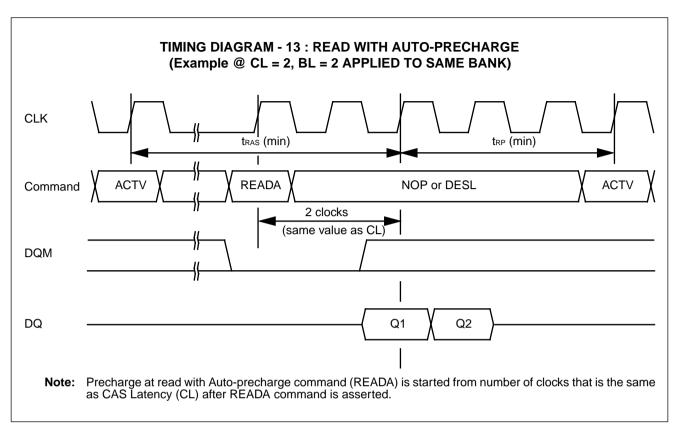


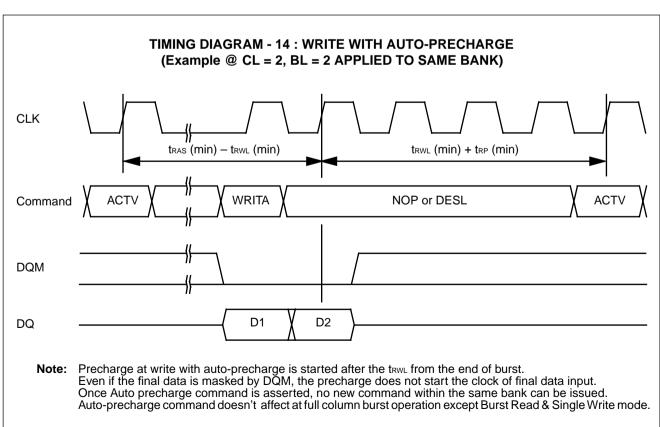


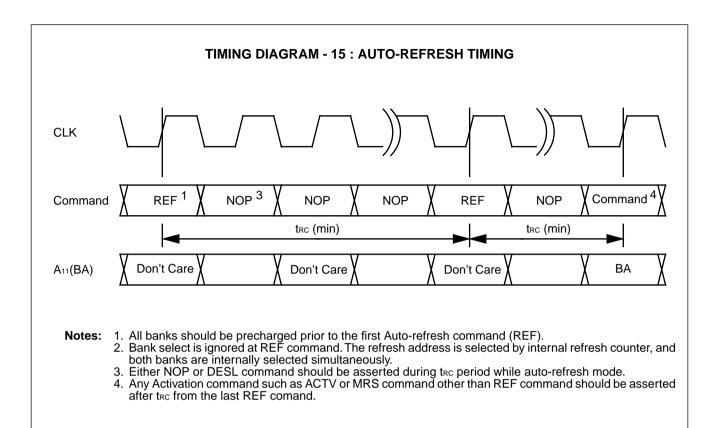


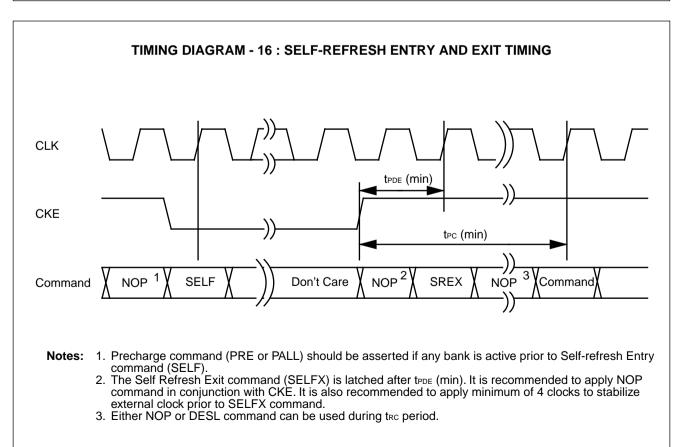
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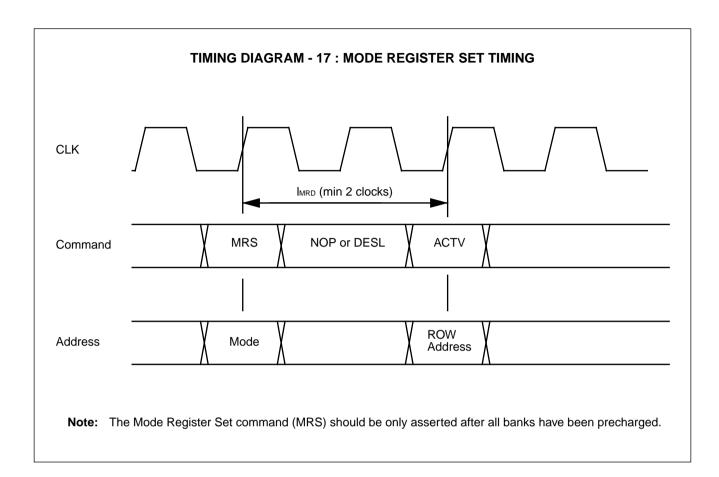






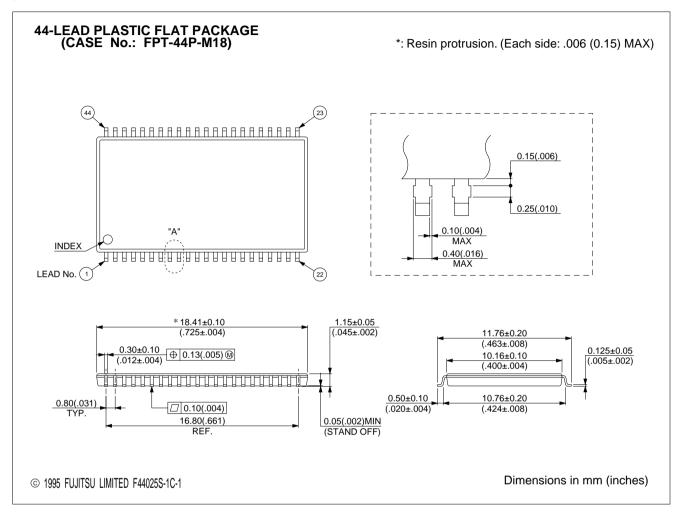






■ PACKAGE DIMENSIONS

Suffix: FN



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